

The use of either glass or teflon insulators compromises the shielding integrity of the inner shutter wall and, if the wiring is to be protected from scatter, additional shielding may be added. The outer shutter wall, if it is intact, protects the user. The electronic circuit (Fig. 1b) depends on normally open contacts so that a relay failure terminates X-ray production. Fig. 1(c) illustrates the system logic.

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Reference

American National Standards Institute (1972). *Radiation Safety for X-ray Diffraction and Fluorescence Analysis Equipment*. Washington, DC: National Bureau of Standards, Handbook 111.

Crystallographers

This section is intended to be a series of short paragraphs dealing with the activities of crystallographers, such as their changes of position, promotions, assumption of significant new duties, honours, etc. Items for inclusion, subject to the approval of the Editorial Board, should be sent to the Executive Secretary of the International Union of Crystallography (J. N. King, International Union of Crystallography, 5 Abbey Square, Chester CH1 2HU, England).

Professor **B. Kamenar**, Laboratory of General and Inorganic Chemistry, Zagreb University, Yugoslavia, was elected President of the European Crystallographic Committee in August 1981, to succeed Dr **O. Kennard** who had been President since 1975. Professor **G. S. D.**

King, Laboratory for Crystallography, The Catholic University of Leuven, Belgium, was elected Vice-President and Professor **P. T. Beurskens**, Department of Inorganic Chemistry and Crystallography, University of Nijmegen, The Netherlands, was re-elected Secretary.

International Union of Crystallography

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Division of Acta Crystallographica

Beginning with Volume 39 in January 1983, *Acta Crystallographica* will be published in three sections:

Section A – Foundations of Crystallography
One Volume, six parts per year

Section B – Structural Science
One Volume, six parts per year

Section C – Crystal Structure Communications
One Volume, twelve parts per year.

The new Section C will also incorporate the journal *Crystal Structure Communications*, which was founded by the X-ray crystallography group at the University of Parma and has up to the present been published by the University of Parma.

An Editorial giving the reasons for the new division of *Acta Crystallographica* has been published in the January issues of *Acta Crystallographica*, Section A and Section B [*Acta Cryst.* (1982), **A38**, 1; **B38**, 1].

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Deposition of Crystal Data

At its meetings in Ottawa, August 1981, the Commission on Journals decided that only Titles and Abstracts will normally be printed for Crystal Data from the middle of 1982, i.e. for manuscripts received after 1 April 1982. All other parts of the contribution will be deposited with the British Library Lending Division. Copies will be available through the Executive Secretary, International Union of Crystallography, 5 Abbey Square, Chester CH1 2HU, England.

The papers will continue to be refereed. In addition, where appropriate, the data will be checked by the Joint Committee on Powder Diffraction Stand-

ards (JCPDS) before publication and assigned a JCPDS reference number, which will be published as part of the Abstract. This will mean that the powder pattern will be included in the Powder Diffraction File at the earliest stage possible.

Where appropriate, a Crystal Data contribution must in future give as much of the information as possible described in "Standards for the Publication of Powder Pattern Data" [*J. Appl. Cryst.* (1981). **14**, 216–217]. In particular, the title and Abstract should include: the name (given in the correct IUPAC form) and (if applicable) the mineral name and locality, the chemical purity, the chemical formula, space group (if known), the unit-cell parameters, the volume of the unit cell, *Z*, the measured and X-ray densities, measurement technique and conditions, radiation used and a description of the powder data and other data deposited. The unit cell parameters, the volume of the unit cell and the measured density should each be accompanied by their e.s.d.

Book Reviews

Works intended for notice in this column should be sent direct to the Book-Review Editor (J. H. Robertson, School of Chemistry, University of Leeds, Leeds LS2 9JT, England). As far as practicable books will be reviewed in a country different from that of publication.

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Scanning electron microscopy/1980. Parts I and II. Edited by *Robert P. Becker* and *Om Johari*. Pp. part I: xvi + 608; part II: xiv + 658. Scanning Electron Microscopy, Inc., P.O. Box 66507 AMF O'Hare (Chicago), IL 60666, USA. Price US \$50 for one part, US \$80 for both parts.

The proceedings of the 1980 Scanning Electron Microscopy Conference held in Chicago from 21 to 25 April are published in four parts. Most of the papers of interest to physical scientists and SEM users in general are contained in part I. The papers in part II are of general interest to biologists but a few of these should also be of interest to physical scientists. Parts III and IV contain papers on biological applications, late papers and papers which were not presented at the conference.

Each part includes a related subject index and a major subject index which also includes some relevant papers in other parts.